

## **DESCRIPTION**

The AM2306 is the N-Channel logic enhancement mode power field effect transistor is produced using high cell density. Advanced trench technology to provide excellent R<sub>DS(ON)</sub>.

This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application, and low in-line power loss are needed in a very small outline surface mount package.

AM2306 is available in a SOT-23 package.

#### ORDERING INFORMATION

Package Type	Part Number			
SOT-23	Го	AM2306E3R		
	E3	AM2306E3VR		
Note	R: Tape & Reel			
Note	V: Green Package			
AiT provides all Pb free products				
Suffix " V " means Green Package				

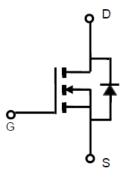
## **FEATURES**

- -30V/3.6A,  $R_{DS(ON)}$ = 45m $\Omega$ (typ.)@V<sub>GS</sub>= 10V
- 30V/2.8A,  $R_{DS(ON)} = 55m\Omega(typ.)@V_{GS} = 4.5V$
- Super high density cell design for extremely low R<sub>DS(ON)</sub>
- Exceptional on-resistance and Maximum DC current capability
- Available in a SOT-23 package.

#### **APPLICATION**

- Power Management in Note book
- Portable Equipment
- DSC
- LCD Display inverter
- Battery Powered System
- DC/DC Converter

## P CHANNEL MOSFET

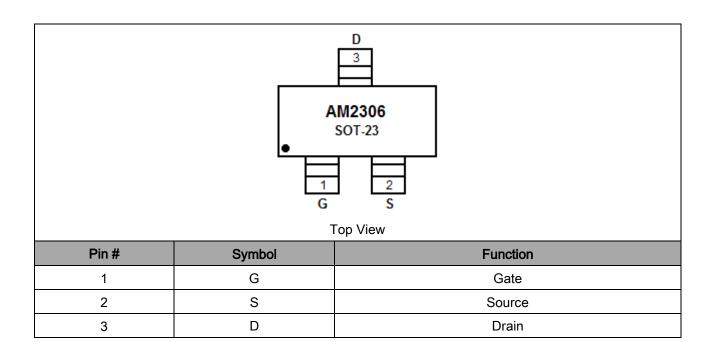


N-Channel

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# PIN DESCRIPTION



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# ABSOLUTE MAXIMUM RATINGS

T<sub>A</sub> = 25°C Unless otherwise noted

V <sub>DSS</sub> , Drain-Source Voltage	
V <sub>GSS</sub> , Gate-Source Voltage	
V <sub>GS</sub> =10V	4.0A
I <sub>DM</sub> , Pulsed Drain Current	
Is, Continuous Source Current (Diode Conduction)	
P <sub>D</sub> , Power Dissipation	
T <sub>A</sub> =25°C	
T <sub>A</sub> =70°C	
T <sub>J</sub> , Operation Junction Temperature	
T <sub>STG</sub> , Storage Temperature Range	

Stress beyond above listed "Absolute Maximum Ratings" may lead permanent damage to the device. These are stress ratings only and operations of the device at these or any other conditions beyond those indicated in the operational sections of the specifications are not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

# THERMAL DATA

Parameter	Symbol	Max	Unit
Thermal Resistance-Junction to Ambient	$R_{\theta JA}$	120	°C/W

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# **ELECTRICAL CHARACTERISTICS**

T<sub>A</sub> = 25°C Unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур.	Max	Units
Static Param	neters					
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	30	-	-	V
$V_{\text{GS(th)}}$	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	1.0	-	2.5	V
I <sub>GSS</sub>	Gate Leakage Current	V <sub>DS</sub> =0V,V <sub>GS</sub> =±20V	-	-	±100	nA
	Zero Gate Voltage Drain	V <sub>DS</sub> =30V,V <sub>GS</sub> =0V	-	-	1	
Current	V <sub>DS</sub> =30V,V <sub>GS</sub> =0V T <sub>J</sub> =55°C	-	-	10	μΑ	
$I_{D(ON)}$	On-State Drain Current	V <sub>DS</sub> ≧5V,V <sub>GS</sub> =10V	6	-	-	Α
R <sub>DS(ON)</sub>	Drain-source On-Resistance	V <sub>GS</sub> =10V,I <sub>D</sub> =3.6A V <sub>GS</sub> =4.5V,I <sub>D</sub> =2.8A	-	45 55	55 60	mΩ
G <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =15V,I <sub>D</sub> =5.0A	-	4.5	-	S
Source-Drain	n Diode		1	•	•	
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1.25A,V <sub>GS</sub> =0V	-	0.8	1.2	V
Dynamic Pa	rameters					
Qg	Total Gate Charge	V <sub>DS</sub> =15V	-	4.5	10	
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> =10V	-	0.8	-	nC
$Q_{\text{gd}}$	Gate-Drain Charge	I <sub>D</sub> ≡2.5A	-	1.0	-	
Ciss	Input Capacitance		-	380	-	
Coss	Output Capacitance	V <sub>DS</sub> =15V	-	70	-	_
Crss	Reverse Transfer Capacitance	V <sub>GS</sub> =0V f=1MHz	-	40	-	pF
t <sub>d(ON)</sub>		V <sub>DD</sub> =15V	-	8	20	
Tr	Turn-On Time	R <sub>L</sub> =15Ω	-	6	16	1
t <sub>d(OFF)</sub>		I <sub>D</sub> =1.0A	-	20	35	nS
Tf	Turn-Off Time	$V_{GEN}$ =10 $V$ $R_{G}$ =6 $\Omega$	-	5	15	

NOTE: 1. Pulse test: pulse width <= 300us, duty cycle<= 2%

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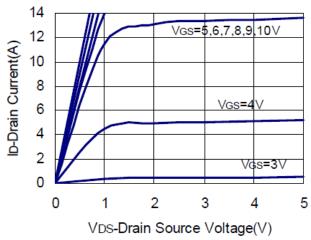
<sup>2.</sup> Static parameters are based on package level with recommended wire-bonding



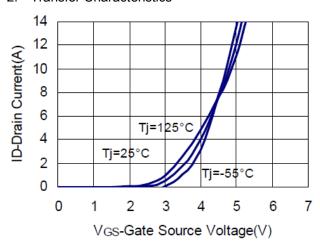
### TYPICAL CHARACTERISTICS

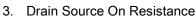
25°C Unless Specified

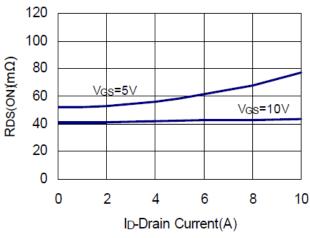
1. Output Characteristics



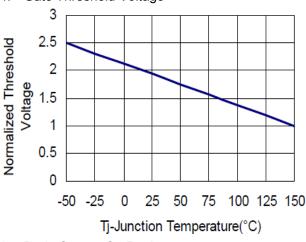
2. Transfer Characteristics





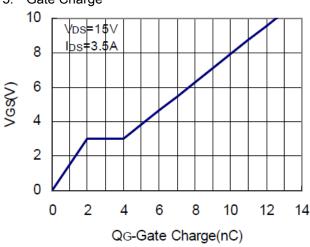


Gate Threshold Voltage

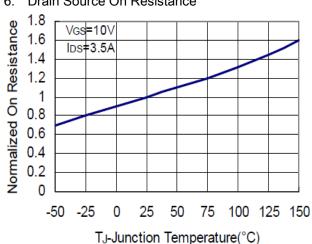


Gate Charge

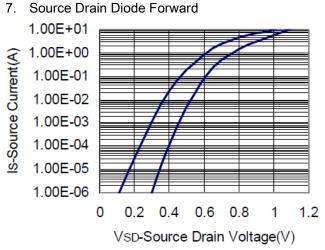
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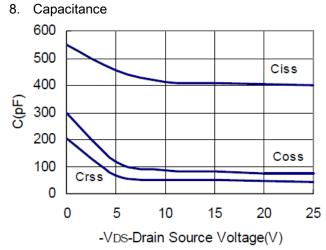


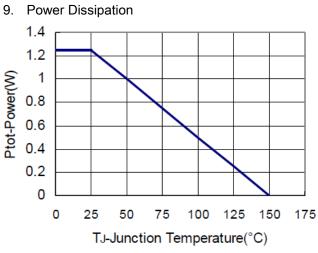
Drain Source On Resistance

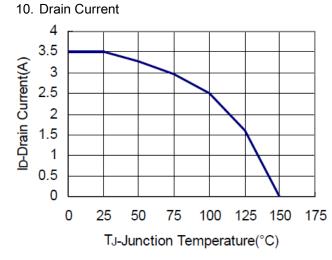


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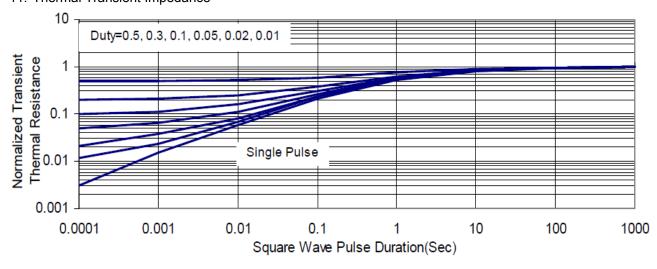








#### 11. Thermal Transient Impedance

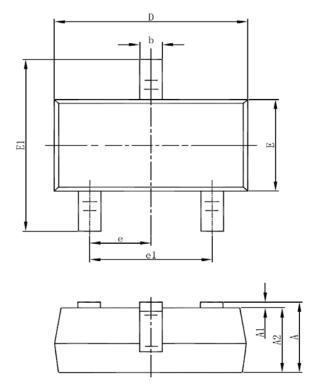


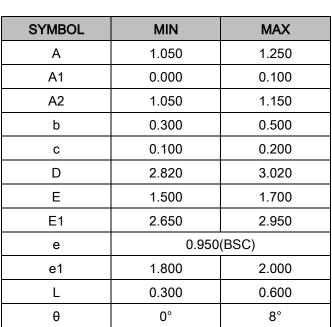
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# **PACKAGE INFORMATION**

Dimension in SOT-23 Package (Unit: mm)







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